



INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	Docket Number (Optional) NSCI-M2900 [P05632]	Application Number 10/616381
	Applicant(s) Douglas Brisbin et al.	
	Filing Date 7/9/2003	Group Art Unit Unknown 2815

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
MCL	AA	5,517,046	05/14/1996	Hsing et al.	257	336	02/06/1995
MCL	AB	6,144,069	11/07/2000	Tung	257	335	08/03/1999
MCL	AC	6,177,834	01/23/2001	Blair et al.	327	566	12/02/1998
MCL	AD	6,297,533	10/02/2001	Mkhitarian	257	336	04/30/1998
MCL	AE	6,548,839	04/15/2003	Strachan et al.	257	204	02/20/2002
MCL	AF	6,566,710	05/20/2003	Strachan et al.	257	341	08/29/2001

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

MCL	AG	D. Brisbin et al., "Design Optimization of N-LDMOS Transistor Arrays for Hot Carrier Lifetime Enhancement," <i>International Reliability Physics Symposium Proceedings 2003</i> , pp. 608-609 (2 pages in length).
MCL	AH	D. Brisbin et al., "Hot Carrier Reliability of N-LDMOS Transistor Arrays for Power BiCMOS Applications," <i>International Reliability Physics Symposium Proceedings 2002</i> , pp. 105-110 (6 pages in length).
MCL	AI	U.S. Patent Application No. 10/266,543, filed October 8, 2002, entitled: "Method and device for improving hot carrier reliability of an LDMOS transistor using drain ring over-drive bias," by Douglas Brisbin et al., 16 pages in length.

Examiner Matthew C. Sullivan	Date Considered 9/14/04
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP/Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	